TRANSMISSION PROPERTIES OF ZITEX IN THE INFRARED TO SUBMILLIMETER

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ABSTRACT

The results of measurements of the refractive index and power absorption coefficient of Zitex at 290K and 77K in the spectral region from 1 to 1000 microns are presented. Zitex is a porous Teflon sheet with a filling factor of ~ 50%, and is manufactured in several varieties as a filter paper. Zitex is found to be an effective IR block, with thin $(200\mu m)$ sheets transmitting less than 1% in the 1-50 μm range while absorbing $\leq 10\%$ at wavelengths longer than $200\mu m$. Some variation in the cutoff wavelength is seen, tending to be a shorter wavelength cutoff for a smaller pore size. Additionally, the thermal conductivity of Zitex at cryogenic temperatures has been measured, and is found to be roughly one-half that of bulk Teflon.

1. INTRODUCTION

To reduce the loading on cold optical elements operating in the far infrared, room temperature radiation must be blocked efficiently while allowing the desired wavelengths to pass unattenuated^[1, 2]. Commonly used materials include blackened polyethylene and Quartz. Unfortunately, the transmittance of black polyethylene is dependent on the size. concentration, and form of the carbon used to blacken it. and varies substantially in its far-infrared properties^[3]. Quartz is a low-loss material when a suitable antireflection coating like Teflon is applied, but this is difficult and restricts the wavelengths over which it can be used as a highly transmissive element^[4]. Teflon itself is a good IR block, but transmits power in the 5-10 μ m range and longward of 50 μ m, limiting its usefulness. Several more absorbing materials, such as Fluorogold and Fluorosint, have been used for low frequency applications, but their slow spectral cut-off characteristics are not ideal for receivers operating near 1 THz^[4, 5].

Zitex is a sintered Teflon material with voids of $1-60\mu$ m and a filling factor of 50%. Several different varieties are

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available, divided into two categories by manufacturing process. Zitex A^[6] is designed to reproduce filter paper. and so has many narrow linear paths through it and is a rough but soft sheet. It is available in 11 grades with effective pore sizes ranging from $3\mu m$ to $45\mu m$ and in thicknesses from 0.13mm (0.005") to 0.64mm (0.025"). Zitex G is made of sintered Teflon spheres of small sizes. resulting in a denser, smoother material. Available in 5 grades, the pore sizes range from $1.5\mu m$ to $5.5\mu m$ and is available in standard thicknesses of 0.10mm (0.004") to 0.38mm (0.015"), although larger thicknesses are available.

Zitex is similar in geometry to glass bead filters, in which dielectric spheres are embedded into a suspending material with a different index of refraction. A single sphere of radius a will scatter strongly for wavelengths $\lambda \leq \pi a(n-1)^{[7]}$. Thus, for Teflon $(n = 1.44^{[8]})$, a sphere of radius 10 μ m produces a shadow for wavelengths shortward of 15 μ m. At short wavelengths, then, a perfectly scattering screen will redistribute the optical power in an incident beam equally in all directions, resulting in a large loss for wellcollimated beams.

2. MEASUREMENTS

Because of the large wavelength range involved, three FTS instruments were used to characterize Zitex. For the nearto mid-infrared (1 - 80 μ m; 10000-125 cm⁻¹) a commercially available Nicolet 60SX spectrometer^[9] was used. The farinfrared (50 - 200 μ m; 200 - 50 cm⁻¹) measurements were made on a Bruker interferometer at JPL. The submillimeter data (200-1000 μ m; 50-10 cm⁻¹) was obtained on an FTS at Caltech^[10]. The focal ratio of the spectrometers was roughly f/4. A perfectly scattering surface would yield a transmission of roughly 0.4% in this case. Table 1 lists the samples we measured.

3. TEFLON

In order that we might characterize qualitatively the difference between bulk Teflon and Zitex sheets. we measured one thin (0.25 mm) and one thick (0.75 mm) sample of plane-parallel Teflon sheet. Figure 1 shows the results of a measurement of the far-infrared transmission of the thick sample near the cut-on region at 50-100 μ m. The sample was measured at room temperature and liquid nitrogen temperature. showing a slight improvement in the transmission when the sample is cold. Figure 2 shows the mid-infrared transmission of the thinner sample. which highlights the fairly narrow regions near 10- $20\mu m$ where the absorption is large.

4. ZITEX G104. G106, G108, G110, G115. A155

The samples of G104 and G106 were measured in the near- to mid-infrared to derive a transmission and an effective absorption coefficient, as shown in figure 3. The absorption coefficient α for a sheet of thickness h is calculated from the transmission T as -Ln(T)/h. Since some wavelength-dependent fraction of the loss (1 - T) is from scattering and some from absorption, the absorption coefficient cannot be used to estimate the transmission of arbitrary thicknesses. It does, however, provide a useful means of comparison with other, more purely absorptive, materials.

Combining sets of data in the nearthrough far-infrared for samples of G108 and G110 allows us to build a more complete picture of the profile of the cut-on

Grade	Pore Size	Thickness	Filling	NIR	FIR	Submm
	(μm)	(mm)	Factor	data	data	data
G104	5-6	0.10	0.45			
G106	4-5	0.16	0.50	X		
G108	3-4	0.20	0.55	X	Х	
G110	1-2	0.25	0.60	X	Х	
G115	1-2	0.41	0.60	X		
G125	~3	3.53	~ 0.5	X		X
A155	2-5	0.27	0.40	X		

Table 1. Zitex samples measured.

* Relative density of Teflon.



Fig. 1.— Far-Infrared transmission of the thick slab of Teflon at 300K and 77K.



Fig. 2.— Mid-Infrared transmission of a 0.25mm thick Teflon sheet, highlighting the regions of good absorption.



Fig. 3.— Transmission and absorption coefficient in nepers/cm of Zitex G104 and G106.

of Zitex near 100μ m, as shown in figure 4. Measurements of G115 and A155 are shown in figure 5. A marked shortening of the cut-on wavelength can be seen in the A155 sample, presumably as a result of its different structure.

5. ZITEX G125

As the thickest of all the samples, the G125 sheet of Zitex was used for the longest wavelengths, covering 400 and 1600 GHz (188 and 750 μ m). Even with a 3.5mm thick slab, the loss was small enough to be below detectability at longer wavelengths. The sample was cooled to 2K in order to determine its suitability as a mid-infrared blocking filter for helium-cooled cryostats. The transmission and effective absorption coefficient are shown in figure 6. The 1400 GHz absorption feature is known as an absorption band seen in cold Teffon^[8].

Combining the data on G125 near

1 THz with data at shorter wavelengths allows us to determine a broadband transmission and absorption coefficient. as shown in figure 7, for the range 20-1000 μ m (300 GHz-15 THz). The effective absorption coefficient as well fit by $\alpha = 23 \exp[(\lambda_{\mu m}/37)^{0.77}]$ nepers/cm. The transmission, neglecting the absorption band, follows $T = \exp(-7000\lambda_{um}^{-1.8})$.

6. MULTIPLE LAYERS

A helium-cooled receiver is likely to have several layers of infrared-blocking filtration in the optical path. As a result, it is natural in the case of a scattering material like Zitex to question its efficacy in a multilayer application. Layering single-, double-, and triple-ply sheets of Zitex in close proximity (limited only by the natural wavy contours of the thin sheets) yields the transmission measurements shown in figure 8. Because the transmission drops more slowly that for



Fig. 4.— Transmission and absorption coefficient in nepers/cm of Zitex G108 and G110 using near-, mid-, and far-infrared data.



Fig. 5.— Transmission of Zitex G115 & A155 in the near- to mid-infrared.



Fig. 6.— Transmission and absorption coefficient in nepers/cm of Zitex G125 between 400 and 1600 GHz (188 and 750μ m).



Fig. 7.— Transmission and absorption of Zitex G125.



Fig. 8.— Transmission of single. double, and triple layers of Zitex in close proximity. The transmission drops more slowly than for a pure absorbing medium, implying strong scattering.

a pure absorbing medium (i.e. $T_3 = T_1^3$ and $T_2 = T_1^2$) in the mid-infrared, we can infer than scattering is the dominant loss mechanism and that multiple sheets are not substantially more effective than single sheets.

If, however, we separate the layers slightly and look at longer wavelengths, the picture changes. Using Zitex A155 sheets spaced by roughly 5mm, we find find the transmission shown in figure 9. At mid-infrared wavelengths, the Zitex still appears to be dominated by scattering, whereas at far-infrared wavelengths, the transmission appears to be increasingly determined by absorption (presumably in the bulk of the Teflon).

7. TEMPERATURE VARIATION

In the case of many materials (e.g., quartz), the absorption of mid-infrared radiation is known to vary as the temperature changes^[11]. To determine if there was any temperature effect in the transmission of Zitex, we measured the transmission of samples of G110 at 300K and 77K in the far-infrared near the cut-on region. No significant variation in the transmission was seen upon cooling (figure 10), which is to be expected for dielectric scattering.

8. REFRACTIVE INDEX

Measuring the refractive index of a material of low dielectric constant is difficult near 1 THz for a nondispersive FTS. Only the thick sample of G125 could be measured, via a determination of the fringe spacing in the 3.5mm thick slab. The fringe spacing, averaged between 13 and 45 cm⁻¹ (200-800 μ m or 400-1350 GHz), was 1.18 cm⁻¹. This yields a refractive index for Zitex of is $n = 1.20 \pm 0.07$ at a temperature of 2K. This



Fig. 9.— Transmission of single and double layers of Zitex in an f/4 beam with 1cm spacing. At mid-IR wavelengths, the Zitex acts as two scattering surfaces; at far-IR wavelengths, like an absorber.



Fig. 10.— Far-Infrared transmission of Zitex at 300K and 77K. No substantial variation is seen.

can be compared to Teflon, which has $n = 1.44^{[8]}$; with a filling factor of $\sim 50\%$, the expected refractive index is n = 1.22, exactly as measured.

9. THERMAL CONDUCTIVITY

The thermal conductance of a thick slab of Zitex was measured in the direction along the sheet using an apparatus developed for the purpose^[12]. At cryogenic temperatures ($T \leq 150$ K), the conductivity of Zitex is found to be well fit by $K(T) = 0.01 T^{0.58} \text{ W K}^{-1} \text{m}^{-1}$. This value is half the bulk conductivity of Teflon. indicating that the porous nature of Zitex does not substantially affect its thermal conductance beyond the geometric reduction. However, since Zitex sheets tend to be thin (~ 0.3mm), even the small power incident on Zitex when used as a near-infrared blocking filter will raise its temperature by a significant fraction. This suggests the use of two layers for good blocking, whereas one Teflon layer might have been sufficient to handle the optical loading. However, since the loss in Zitex at long wavelengths is so low, this solution is likely to be more efficient than the use of Teflon.

10. CONCLUSIONS

We have measured the refractive index and power absorption coefficient of Zitex at 290K and 77K in the spectral region from 2 to 200 microns. Its absorption at wavelengths longer than this is found to be extremely small, and with an index of refraction of n = 1.2, there is very little reflection loss. Zitex is an effective IR block when used at wavelengths longward of $200\mu m$, having lower absorption/reflection losses than black polyethylene or quartz and better IR blocking characteristics than Teflon.

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